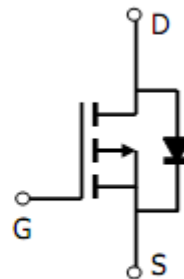
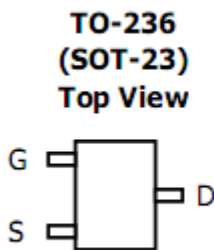


### General Description

The HT3401 uses advanced trench technology to Provide excellent RDS(ON),low gate change and Operation with gate voltages as low as 2.5V.This Device is suitable for use as a load switch or in PWM applications. Standard product HT3401 is Pb-free (meets ROHS & Sony 259 specifications).

### Features

- $V_{DS}(V)=-30V$
- $I_D=-4.2A(V_{GS}=-10V)$
- $R_{DS(ON)}<50m\Omega (V_{GS}=-10V)$
- $R_{DS(ON)}<65m\Omega (V_{GS}=-4.5V)$
- $R_{DS(ON)}<120m\Omega (V_{GS}=-2.5V)$



### Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		VDS	-30	V	
Gate-Source Voltage		VGS	±12	V	
Continuous Drain Current (A)	TA=25°C	ID	-4.2	A	
	TA=70°C		-3.5		
Junction and Storage Temperature Range		IDM	-3.0		
Power Dissipation (A)	TA=25°C	PD	1.4	W	
	TA=70°C		1		
Junction and Storage Temperature Range		TJ,TSTG	-55 to 150	°C	
<b>Thermal Characteristics</b>					
Parameter		Symbol	Typ	Max	Units
Maximum junction-to-Ambient(A)	t ≤ 10s	RθJA	65	90	° C/W
	Steady-State		85	125	
Maximum junction-to-Lead(C)	Steady-State	RθJL	43	60	° C/W

## Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	ID=-250μA, VGS=0V	-30			V
IDSS	Zero Gate Voltage Drain Current	VDS=-24V, VGS=0V			-1	μA
		TJ=55°C			-5	
IGSS	Gate-Body leakage current	VDS=0V, VGS=±12V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	VDS=VGS ID=-250μA	-0.7	-1	-1.3	V
ID(ON)	On state drain current	VGS=-4.5V, VDS=-5V	-25			A
RDS(ON)	Static Drain-Source On-Resistance	VGS=-10V, ID=-4.2A		42	50	mΩ
		TJ=125°C			75	
		VGS=-4.5V, ID=-4A		53	65	mΩ
		VGS=-2.5V, ID=-1A		80	120	mΩ
g <sub>FS</sub>	Forward Transconductance	VDS=-5V, ID=-5A	7	11		S
V <sub>SD</sub>	Diode Forward Voltage	IS=-1A, VGS=0V		-0.75	-1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				-2.2	A
I <sub>SM</sub>	Pulsed Body-Diode Current <sup>B</sup>				-30	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	VGS=0V, VDS=-15V, f=1MHz		954		pF
C <sub>oss</sub>	Output Capacitance			115		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			77		pF
R <sub>g</sub>	Gate resistance	VGS=0V, VDS=0V, f=1MHz		6		Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub>	Total Gate Charge	VGS=4.5V, VDS=-15V, ID=-4A		9.4		nC
Q <sub>gs</sub>	Gate Source Charge			2		nC
Q <sub>gd</sub>	Gate Drain Charge			3		nC
t <sub>D(on)</sub>	Turn-On Delay Time	VGS=-10V, VDS=-15V, RL=3.6Ω, RGEN=6Ω		6.3		nC
t <sub>r</sub>	Turn-On Rise Time			3.2		ns
t <sub>D(off)</sub>	Turn-Off Delay Time			38.2		ns
t <sub>f</sub>	Turn-Off Fall Time			12		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	IF=-4A, di/dt=100A/μs		20.2		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	IF=-4A, di/dt=100A/μs		11.2		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The

value in any a given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using  $<300 \mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2

FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

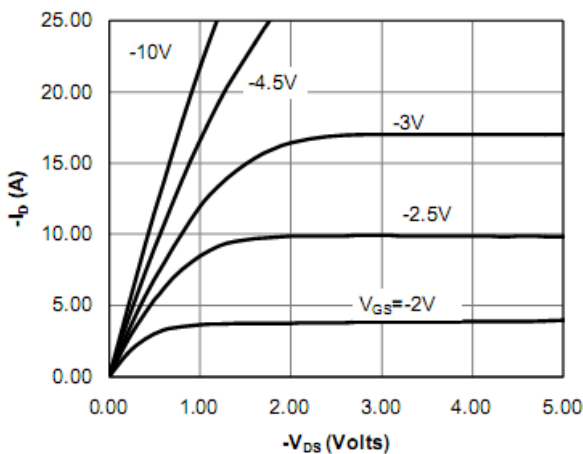


Fig 1: On-Region Characteristics

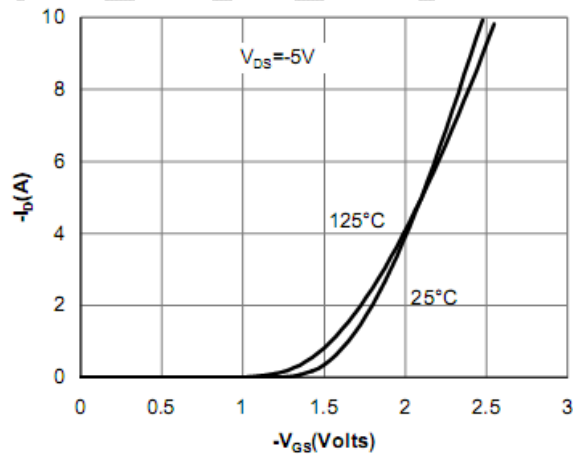


Figure 2: Transfer Characteristics

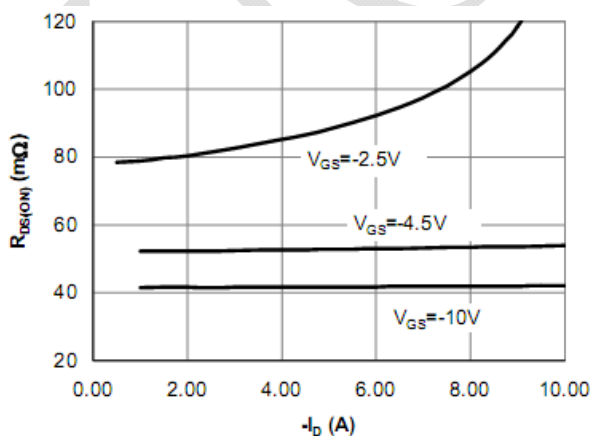


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

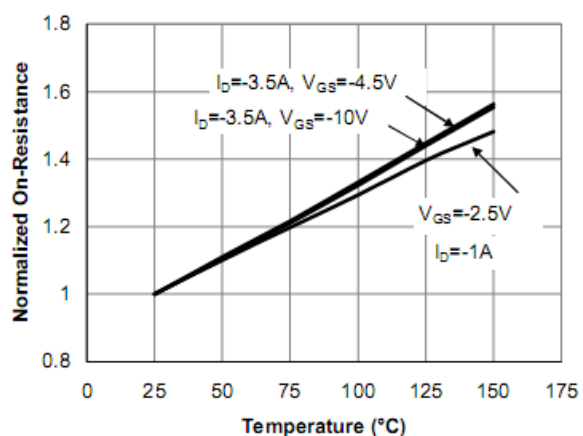


Figure 4: On-Resistance vs. Junction Temperature

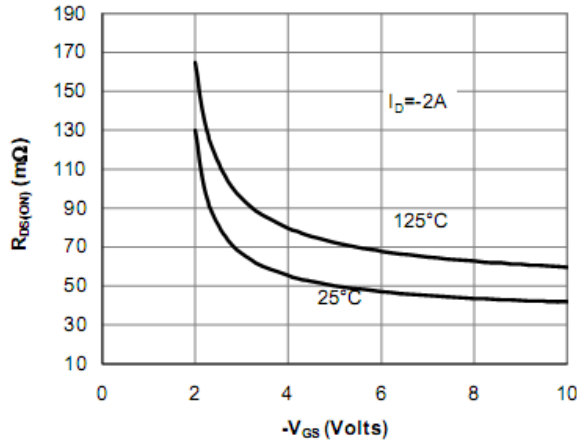


Figure 5: On-Resistance vs. Gate-Source Voltage

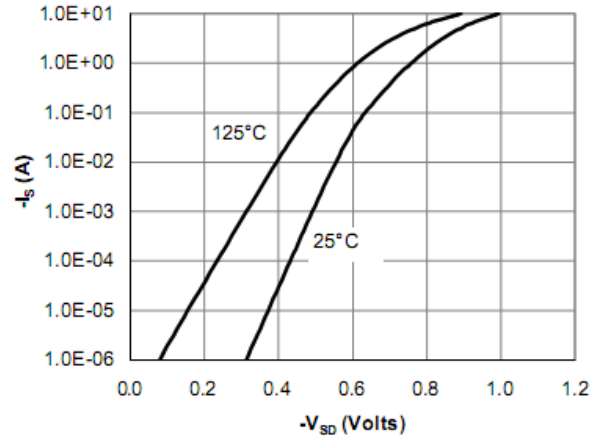


Figure 6: Body-Diode Characteristics

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

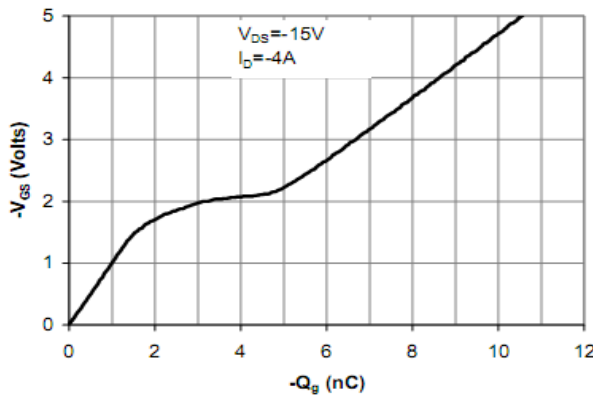


Figure 7: Gate-Charge Characteristics

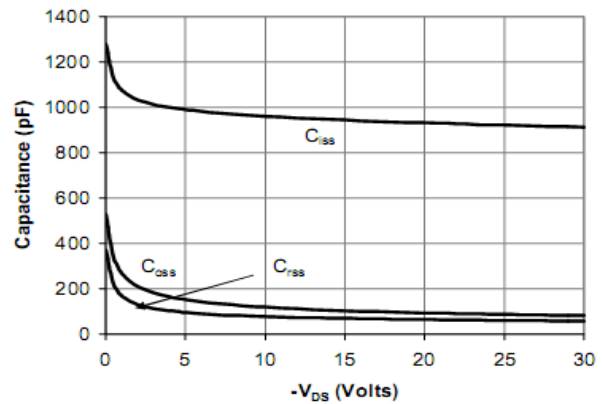


Figure 8: Capacitance Characteristics

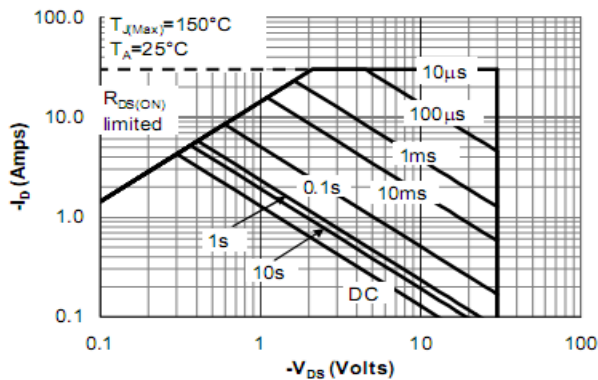


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

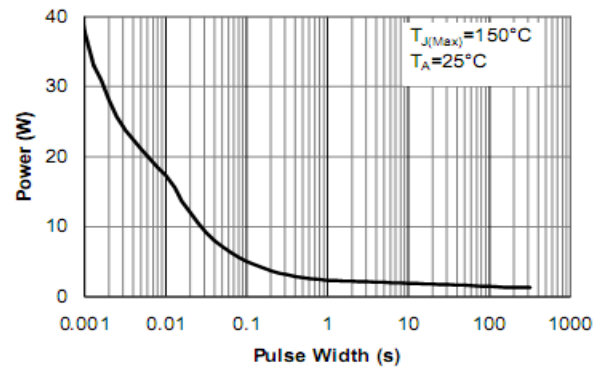


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

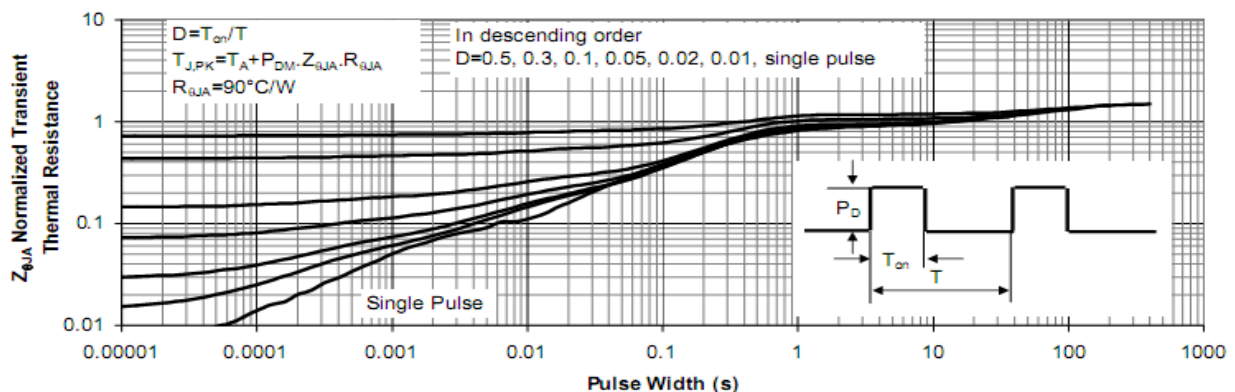


Figure 11: Normalized Maximum Transient Thermal Impedance

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